## Search Notes

Application/Control No.	Applicant(s)/Patent Under Reexamination
1066278911549068	CHEFALAS ET AL.BARKER ET AL.
Examiner	Art Unit
Veillard, JacquesJACQUES VEILLARD	21652165

SEARCHED			
Class	Subclass	Date	Examiner
707707	2, 3, 4, 5, 101, 102 with limited keywords (Updated 12/15/2008)1-4, 5, 100-102, 200-202, 205 With Limited Keywords (Updated 12/18/2008	6/17/200812/07/ 2006	J.VJ.V
709	203, 220-225, 236, 246 With limited Keywords (Updated 12/18/2008)	12/07/2006	J.V
715	501.1, 513, 826 With limited Keywords (Updated 12/2008)	12/07/2006	J.V

SEARCH NOTES			
Search Notes	Date	Examiner	
EIC Database Plus From TC2100	6/12/2008	J.V	
Palm Inventors Search	6/17/2008	J.V	
East Electronic Database Search Using limited keywords (Updated 12/15/2008)	6/18/2008	J.V	
ACM Electronic Databases SearchEIC Plus database search	6/18/200811/21/ 2006	J.VJ.V	
Consulted with G. Robinson P.E AU 2168, reviewed the claims	12/06/2006	J.V	
Consulted with L.Wassum	12/07/2006	J.V	
Consulted with 101 panel, M. Bookbinder confirm that claims 8, and 17-23 are non-statutory	12/07/2006	J.V	
East Electronic Database search Using Limited Keywords (Updated 12/18/2008)	12/07/2006	J.V	
Inventor search for possible double patenting	12/07/2006	J.V	
New EIC Plus Databases Search	12/18/2008	J.V	

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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